L Number	Hits	Search Text	DB	Time stamp
1	11	"5012105"	USPAT; US-PGPUB;	2003/10/17 13:32
2	3002	(250/492.22,492.2,492.23).CCLS.	EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2003/10/17 13:33
3	3501	(250/492.22,492.2,492.23,398).CCLS.	DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/10/17 13:34
4	8190	multibeam or multi-beam or (multiple adj (aperture or beam or beamlet)) and (electron or charged-particle or (charged adj particle))	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/10/17
5	185	<pre>(multibeam or multi-beam or (multiple adj (aperture or beam or beamlet)) and (electron or charged-particle or (charged adj particle))) and (beamlet or subbeam</pre>	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/10/17 13:36
6	112	or sub-beam) ((multibeam or multi-beam or (multiple adj (aperture or beam or beamlet)) and (electron or charged-particle or (charged adj particle))) and (beamlet or subbeam	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/10/17 13:37
7	71	or sub-beam)) and aperture (((multibeam or multi-beam or (multiple adj (aperture or beam or beamlet)) and (electron or charged-particle or (charged adj particle))) and (beamlet or subbeam	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/10/17 13:37
8	10	or sub-beam) and aperture) and deflect\$4 (((multibeam or multi-beam or (multiple adj (aperture or beam or beamlet)) and (electron or charged-particle or (charged adj particle))) and (beamlet or subbeam	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/10/17
9	46	or sub-beam)) and aperture) and deflect\$4) and (different with pattern)	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/10/17 13:39
10	33	<pre>deflect\$4) and simultan\$8 (((((multibeam or multi-beam or (multiple adj (aperture or beam or beamlet)) and (electron or charged-particle or (charged adj particle))) and (beamlet or subbeam or sub-beam)) and aperture) and</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 13:45
11	45	adj (aperture or beam or beamlet)) and (electron or charged-particle or (charged adj particle))) and (beamlet or subbeam or sub-beam)) and aperture) and	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 13:52
12	7	<pre>deflect\$4) and simultan\$8) and (independent\$3 or individual\$4) ((((((multibeam or multi-beam or (multiple adj (aperture or beam or beamlet)) and (electron or charged-particle or (charged adj particle))) and (beamlet or subbeam or sub-beam)) and aperture) and deflect\$4)</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 13:51
		and simultan\$8) and (independent\$3 or individual\$4)) and ((250/492.22,492.2,492.23,398).CCLS.)		

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13	17	<pre>(((((multibeam or multi-beam or (multiple adj (aperture or beam or beamlet)) and (electron or charged-particle or (charged</pre>	USPAT; US-PGPUB; EPO; JPO;	2003/10/17 13:53
		<pre>adj particle))) and (beamlet or subbeam or sub-beam)) and aperture) and deflect\$4) and simultan\$8) and</pre>	DERWENT; IBM_TDB	
		((independent\$3 or individual\$4) with deflect\$5)		
14	9	"5359202"	USPAT; US-PGPUB;	2003/10/17 14:01
			EPO; JPO; DERWENT;	
		WEO 444 45 W	IBM_TDB	2002/10/17
15	11	"5841145"	USPAT; US-PGPUB;	2003/10/17 14:03
ļ ,			EPO; JPO; DERWENT;	
			IBM_TDB	
16	10	"5977548"	USPAT;	2003/10/17 14:04
			US-PGPUB; EPO; JPO;	14:04
			DERWENT;	
			IBM TDB	

L	Hits	Search Text	DB	Time stamp
Number 1	556	((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different\$4 with (imag\$5	USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/10/17 16:37
2	31	or pattern\$4))	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17
3	26	multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different\$4 with (imag\$5 or pattern\$4))) and (beamlet or subbeam or sub-beam)) and (different\$4 near4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:38
4	. 24	<pre>(imag\$5 or pattern\$4)) (((((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different\$4 with (imag\$5 or pattern\$4))) and (beamlet or subbeam or sub-beam)) and (different\$4 near4 (imag\$5 or pattern\$4))) and (independent\$3 or individual\$4) and deflect\$5</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:38
5	19	<pre>((((((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different\$4 with (imag\$5 or pattern\$4))) and (beamlet or subbeam or sub-beam)) and (different\$4 near4 (imag\$5 or pattern\$4))) and (independent\$3 or individual\$4) and deflect\$5) and (etch\$3 or writing or</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:05
6	353	lithograph\$3) (((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different\$4 with (imag\$5 or pattern\$4))) and (different\$4 near4 (imag\$5 or pattern\$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:05
7	162	(((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different\$4 with (imag\$5 or pattern\$4))) and (different\$4 near4 (imag\$5 or pattern\$4))) and (independent\$3 or individual\$4) and deflect\$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17
8	118	(((((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different\$4 with (imag\$5 or pattern\$4))) and (different\$4 near4 (imag\$5 or pattern\$4))) and (independent\$3 or individual\$4) and deflect\$5) and (etch\$3 or writing or	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:39
9		lithograph\$3) ((((((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different\$4 with (imag\$5 or pattern\$4))) and (different\$4 near4 (imag\$5 or pattern\$4))) and (independent\$3 or individual\$4) and deflect\$5) and (etch\$3 or writing or lithograph\$3)) and ((independent\$3 or individual\$4) with deflect\$5)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:39

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				0000/10/17
10	0	09/375627	USPAT;	2003/10/17
			US-PGPUB;	16:28
			EPO; JPO;	
			DERWENT;	
		(00/075607)	<pre>IBM_TDB USPAT;</pre>	2003/10/17
11	0	(09/375627).CCLS.	US-PGPUB;	16:28
1			EPO;	10.20
			DERWENT	
10	7	 "375627"	USPAT;	2003/10/17
12	'	"3/362/"	US-PGPUB;	16:28
			EPO; JPO;	10.20
			DERWENT;	
			IBM TDB	
1.3	2	Hans adj Loschner	USPAT;	2003/10/17
13	4	nans adj boscimer	US-PGPUB;	16:29
			EPO; JPO;	10.23
			DERWENT;	
			IBM TDB	
14	2	5637951.URPN.	USPAT	2003/10/17
14	4	303/331.UNFN.	Jorn	16:34
1.5	6	("4675572" "4940916" "4990766"	USPAT	2003/10/17
15	"	"5103144" "5363021" "5528103").PN.	*****	16:35
1.0	606	((multiple adj (beam or aperture)) or	USPAT;	2003/10/17
16	606	multibeam or multi-beam or multi-electron	US-PGPUB;	16:37
		or multielectron) and (electron or	EPO; JPO;	1 20.07
		charged-particle or (charged adj	DERWENT;	
		particle)) and (different\$4 with (imag\$5	IBM TDB	
		or pattern\$4))		
17	31	l •	USPAT;	2003/10/17
1 1	"	multibeam or multi-beam or multi-electron	US-PGPUB;	16:38
1		or multielectron) and (electron or	EPO; JPO;	
i		charged-particle or (charged adj	DERWENT;	
		particle)) and (different\$4 with (imag\$5	IBM TDB	
		or pattern\$4))) and (beamlet or subbeam		
		or sub-beam)		
18	380	1	USPAT;	2003/10/17
1 10		multibeam or multi-beam or multi-electron	US-PGPUB;	16:38
		or multielectron) and (electron or	EPO; JPO;	
		charged-particle or (charged adj	DERWENT;	
		particle)) and (different\$4 with (imag\$5	IBM TDB	
1		or pattern\$4))) and (different\$4 near4		
		(imag\$5 or pattern\$4))		
19	171	((((multiple adj (beam or aperture)) or	USPAT;	2003/10/17
		multibeam or multi-beam or multi-electron	US-PGPUB;	16:38
		or multielectron) and (electron or	EPO; JPO;	
		charged-particle or (charged adj	DERWENT;	
		particle)) and (different\$4 with (imag\$5	IBM_TDB	
		or pattern\$4))) and (different\$4 near4	1	
		(imag\$5 or pattern\$4))) and		
		(independent\$3 or individual\$4) and		
		deflect\$5		2002/10/17
20	127		USPAT;	2003/10/17
		multibeam or multi-beam or multi-electron	US-PGPUB;	16:39
		or multielectron) and (electron or	EPO; JPO;	
		charged-particle or (charged adj	DERWENT;	
		particle)) and (different\$4 with (imag\$5	IBM_TDB	
		or pattern\$4))) and (different\$4 near4		
		(imag\$5 or pattern\$4))) and		
		(independent\$3 or individual\$4) and		
		deflect\$5) and (etch\$3 or writing or		
		lithograph\$3)	L	

21	39	(((((multiple adj (beam or aperture)) or	USPAT;	2003/10/17
		multibeam or multi-beam or multi-electron	US-PGPUB;	16:39
		or multielectron) and (electron or	EPO; JPO;	
		charged-particle or (charged adj	DERWENT;	
		particle)) and (different\$4 with (imag\$5	IBM TDB	
		or pattern\$4))) and (different\$4 near4		
		(imag\$5 or pattern\$4))) and		
	ļ	(independent\$3 or individual\$4) and		
		deflect\$5) and (etch\$3 or writing or		
1		lithograph\$3)) and ((independent\$3 or		
		individual\$4) with deflect\$5)		
22	34		USPAT;	2003/10/17
		or multibeam or multi-beam or	US-PGPUB;	16:49
		multi-electron or multielectron) and	EPO; JPO;	
		(electron or charged-particle or (charged	DERWENT;	
		adj particle)) and (different\$4 with	IBM TDB	
		(imag\$5 or pattern\$4))) and (different\$4	_	
		near4 (imag\$5 or pattern\$4))) and		
		(independent\$3 or individual\$4) and		
		deflect\$5) and (etch\$3 or writing or		
		lithograph\$3)) and ((independent\$3 or		
	1	individual\$4) with deflect\$5)) and		
		aperture		

L Number	Hits	Search Text	DB	Time stamp
1	556	((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or	USPAT; US-PGPUB;	2003/10/17 16:37
		charged-particle or (charged adj particle)) and (different\$4 with (imag\$5 or pattern\$4))	EPO; JPO; DERWENT; IBM TDB	10.07
2	31	1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:38
3	26	l	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:38
4	24	<pre>(((((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different\$4 with (imag\$5 or pattern\$4))) and (beamlet or subbeam or sub-beam)) and (different\$4 near4 (imag\$5 or pattern\$4))) and (independent\$3 or individual\$4) and deflect\$5</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:38
5	19		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:05
6	353	<pre>(((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different\$4 with (imag\$5 or pattern\$4))) and (different\$4 near4 (imag\$5 or pattern\$4))</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:05
7	162	(((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different\$4 with (imag\$5 or pattern\$4))) and (different\$4 near4 (imag\$5 or pattern\$4))) and (independent\$3 or individual\$4) and deflect\$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:06
8	118	1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:39
9	32		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:39

		L00 (275 C07	HCDAM.	2003/10/17
10	0	09/375627	USPAT; US-PGPUB;	16:28
			EPO; JPO;	10.20
			DERWENT;	
			IBM TDB	
11	ا ا	(09/375627).CCLS.	USPAT;	2003/10/17
**		(00,0000,0000	US-PGPUB;	16:28
			EPO;	
ŀ			DERWENT	
12	7	"375627"	USPAT;	2003/10/17
			US-PGPUB;	16:28
			EPO; JPO;	
			DERWENT;	
1		**	IBM_TDB USPAT;	2003/10/17
13	2	Hans adj Loschner	US-PGPUB;	16:29
			EPO; JPO;	10.29
			DERWENT;	
			IBM TDB	
14	2	5637951.URPN.	USPAT	2003/10/17
* *	_			16:34
15	6		USPAT	2003/10/17
		"5103144" "5363021" "5528103").PN.		16:35
16	606		USPAT;	2003/10/17
		multibeam or multi-beam or multi-electron	US-PGPUB;	16:37
		or multielectron) and (electron or	EPO; JPO;	
		charged-particle or (charged adj	DERWENT;	
		particle)) and (different\$4 with (imag\$5	IBM_TDB	
1.7		or pattern\$4))	USPAT;	2003/10/17
17	31	(((multiple adj (beam or aperture)) or multibeam or multi-beam or multi-electron	US-PGPUB;	16:38
		or multielectron) and (electron or	EPO; JPO;	1
	1	charged-particle or (charged adj	DERWENT;	
		particle)) and (different\$4 with (imag\$5	IBM TDB	
		or pattern\$4))) and (beamlet or subbeam	_	
		or sub-beam)		
18	380		USPAT;	2003/10/17
		multibeam or multi-beam or multi-electron	US-PGPUB;	16:38
		or multielectron) and (electron or	EPO; JPO;	
		charged-particle or (charged adj	DERWENT;	
		particle)) and (different\$4 with (imag\$5 or pattern\$4))) and (different\$4 near4	IBM_TDB	
		or pattern\$4))) and (different\$4 hear4 (imag\$5 or pattern\$4))		
19	171		USPAT;	2003/10/17
13	''	multibeam or multi-beam or multi-electron	US-PGPUB;	16:38
		or multielectron) and (electron or	EPO; JPO;	
		charged-particle or (charged adj	DERWENT;	
		particle)) and (different\$4 with (imag\$5	IBM_TDB	
1		or pattern\$4))) and (different\$4 near4		
		(imag\$5 or pattern\$4))) and		
		(independent\$3 or individual\$4) and		
	1	deflect\$5	IICDATE.	2003/10/17
20	127	(((((multiple adj (beam or aperture)) or multibeam or multi-beam or multi-electron	USPAT; US-PGPUB;	16:39
		or multipleam or multi-beam of multi-election or	EPO; JPO;	10.00
1		charged-particle or (charged adj	DERWENT;	
		particle)) and (different\$4 with (imag\$5	IBM TDB	
		or pattern\$4))) and (different\$4 near4	_	
		(imag\$5 or pattern\$4))) and		
	1	(independent\$3 or individual\$4) and		
	1	deflect\$5) and (etch\$3 or writing or		
		lithograph\$3)		<u> </u>

21	39	(((((multiple adj (beam or aperture)) or	USPAT;	2003/10/17
21]	multibeam or multi-beam or multi-electron	US-PGPUB;	16:39
		or multielectron) and (electron or	EPO; JPO;	10.05
		charged-particle or (charged adj	DERWENT;	
		particle)) and (different\$4 with (imag\$5	IBM TDB	
		or pattern\$4))) and (different\$4 near4	1011_100	
İ		(imag\$5 or pattern\$4))) and		
		(independent\$3 or individual\$4) and		
	1	deflect\$5) and (etch\$3 or writing or		
		lithograph\$3)) and ((independent\$3 or		
		individual\$4) with deflect\$5)		
22	34		USPAT;	2003/10/17
22] 34	or multibeam or multi-beam or	US-PGPUB;	16:49
1		multi-electron or multielectron) and	EPO; JPO;	
		(electron or charged-particle or (charged		
		adj particle)) and (different\$4 with	IBM TDB	
		(imag\$5 or pattern\$4))) and (different\$4	15155	
		near4 (imag\$5 or pattern\$4))) and		
	1	(independent\$3 or individual\$4) and		
		deflect\$5) and (etch\$3 or writing or		
		lithograph\$3)) and ((independent\$3 or		
		individual\$4) with deflect\$5)) and		
		aperture		
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L Number	Hits	Search Text	DB	Time stamp
1	1966	·	USPAT;	2003/10/17
		multi-aperture or multi-aperture or (multiple adj beam)) and simultaneous\$3 and pattern\$3	US-PGPUB; EPO; JPO; DERWENT;	18:25
		•	IBM_TDB	
2	696	((mulitbeam or mulit-beam or multi-aperture or	USPAT; US-PGPUB;	2003/10/17
		(multiple adj beam)) and simultaneous\$3	EPO; JPO;	
		and pattern\$3) and ((different or var\$5) near4 (pattern\$4 or imag\$5))	DERWENT; IBM TDB	
3	449	(((mulitbeam or mulit-beam or	USPAT;	2003/10/17
		multi-aperture or multi-aperture or (multiple adj beam)) and simultaneous\$3	US-PGPUB; EPO; JPO;	17:59
		and pattern\$3) and ((different or var\$5)	DERWENT;	
		near4 (pattern\$4 or imag\$5))) and . aperture	IBM_TDB	
4	627	(((mulitbeam or mulit-beam or	USPAT;	2003/10/17
		multi-aperture or multi-aperture or (multiple adj beam)) and simultaneous\$3	US-PGPUB; EPO; JPO;	18:01
		and pattern\$3) and ((different or var\$5)	DERWENT;	
		near4 (pattern\$4 or imag\$5))) and (individual\$4 or independent\$4)	IBM_TDB	
5	30	114 and (etch\$4 or writing)	USPAT;	2003/10/17
			US-PGPUB; EPO; JPO;	18:01
			DERWENT;	
6	2905	(mulitbeam or mulit-beam or	IBM_TDB USPAT;	2003/10/17
		multi-aperture or multi-aperture or	US-PGPUB;	18:15
		(multiple adj beam)) and simultaneous\$3	EPO; JPO; DERWENT;	
-	260	//www.lith.com on mulit hoom on	IBM_TDB USPAT;	2003/10/17
7	268	((mulitbeam or mulit-beam or multi-aperture or	US-PGPUB;	18:04
		(multiple adj beam)) and simultaneous\$3)	EPO; JPO; DERWENT;	
		and lithograph\$3	IBM_TDB	
8	180	(((mulitbeam or mulit-beam or multi-aperture or multi-aperture or	USPAT; US-PGPUB;	2003/10/17 18:06
		(multiple adj beam)) and simultaneous\$3)	EPO; JPO;	
		and lithograph\$3) and (electron or ion or charged-particle or (charged adj	DERWENT; IBM TDB	
		particle))	_	0000 (00 (17
9	830	((mulitheam or mulit-beam or multi-aperture or multi-aperture or	USPAT; US-PGPUB;	2003/10/17 18:06
		(multiple adj beam)) and simultaneous\$3)	EPO; JPO;	
		and (electron or ion or charged-particle or (charged adj particle))	DERWENT; IBM TDB	
10	165	(mulitbeam or mulit-beam or	USPĀT;	2003/10/17
		multi-aperture or multi-aperture or (multiple adj beam)) and ((etch\$4 or	US-PGPUB; EPO; JPO;	18:11
		writ\$4) near4 (different or vari\$5))	DERWENT;	
11	830	(mulitbeam or mulit-beam or	IBM_TDB USPAT;	2003/10/17
		multi-aperture or multi-aperture or (multiple adj beam)) and simultaneous\$3	US-PGPUB; EPO; JPO;	18:20
		and (electron or ion or charged-particle	DERWENT;	
12	744	or (charged adj particle)) ((mulitbeam or mulit-beam or	IBM_TDB USPAT;	2003/10/17
16	'33	multi-aperture or multi-aperture or	US-PGPUB;	18:21
		(multiple adj beam)) and simultaneous\$3 and (electron or ion or charged-particle	EPO; JPO; DERWENT;	
	_	or (charged adj particle))) and different	IBM_TDB	2002/10/17
14	0	((((mulitbeam or mulit-beam or multi-aperture or multi-aperture or	USPAT; US-PGPUB;	2003/10/17
		(multiple adj beam)) and simultaneous\$3	EPO; JPO;	
		and (electron or ion or charged-particle or (charged adj particle))) and	DERWENT; IBM_TDB	
		different) and pattern\$3) and abberration		

1.3	F 40	[///www]ithaam an mulit-haam ar	USPAT;	2003/10/17
13	549	(((mulitbeam or mulit-beam or	1	
		multi-aperture or multi-aperture or	US-PGPUB;	18:22
		(multiple adj beam)) and simultaneous\$3	EPO; JPO;	
		and (electron or ion or charged-particle	DERWENT;]
		or (charged adj particle))) and	IBM TDB	
		different) and pattern\$3	_	
15	402	(mulitbeam or mulit-beam or	USPAT;	2003/10/17
		multi-aperture or multi-aperture or	US-PGPUB;	18:28 .
		(multiple adj beam)) and simultaneous\$3	EPO; JPO;	
		and (different near2 (image or	DERWENT;	
		pattern\$3))	IBM TDB	
16	9	((mulitheam or mulit-beam or	USPAT;	2003/10/17
10		multi-aperture or multi-aperture or	US-PGPUB;	18:29
		(multiple adj beam)) and simultaneous\$3	EPO; JPO;	
	ļ	and (different near2 (image or	DERWENT;	
		pattern\$3))) and ((writ\$3 or etch\$4)	IBM TDB	
		with (different near2 (image or		
				1
L	<u> </u>	pattern\$3)))	L	<u> </u>